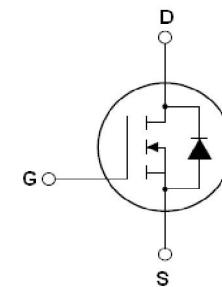


FEATURES

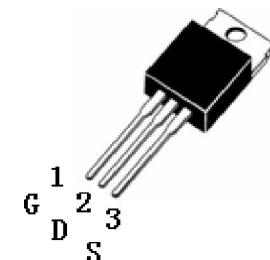
- Advanced trench process technology
- avalanche energy, 100% test
- Fully characterized avalanche voltage and current
- Lead free product

ID =84A
BV=60V
R_{DS(on)}=8mΩ



DESCRIPTION

The SSF6008 is a new generation of high voltage and low current N-Channel enhancement mode trench power MOSFET. This new technology increases the device reliability and electrical parameter repeatability. SSF6008 is assembled in high reliability and qualified assembly house.



APPLICATIONS

- Power switching application

SSF6008 Top View (T0-220)

Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @T _c =25°C	Continuous drain current,VGS@10V	84	A
I _D @T _c =100°C	Continuous drain current,VGS@10V	76	
I _{DM}	Pulsed drain current ①	310	
P _D @T _C =25°C	Power dissipation	181	W
	Linear derating factor	1.5	W/C
V _{GS}	Gate-to-Source voltage	±20	V
E _{AS}	Single pulse avalanche energy ②	400	mJ
E _{AR}	Repetitive avalanche energy ①	20	mJ
dv/dt	Peak diode recovery voltage	30	v/ns
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +175	°C

Thermal Resistance

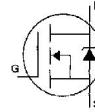
	Parameter	Min.	Typ.	Max.	Units
R _{θJC}	Junction-to-case	—	0.83	—	C/W
R _{θJA}	Junction-to-ambient	—	—	62	

Electrical Characteristics @T_J=25 °C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV _{DSS}	Drain-to-Source breakdown voltage	60	—	—	V	V _{GS} =0V,I _D =250μA
R _{DS(on)}	Static Drain-to-Source on-resistance	—	5.5	8	mΩ	V _{GS} =10V,I _D =30A
V _{GS(th)}	Gate threshold voltage	2.0	—	4.0	V	V _{DS} =V _{GS} ,I _D =250μA
I _{DSS}	Drain-to-Source leakage current	—	—	2	μA	V _{DS} =60V,V _{GS} =0V
		—	—	10		V _{DS} =60V, V _{GS} =0V,T _J =150°C
I _{GSS}	Gate-to-Source forward leakage	—	—	100	nA	V _{GS} =20V

	Gate-to-Source reverse leakage	—	—	-100		V _{GS} =-20V
Q _g	Total gate charge	—	90	—	nC	I _D =30A, V _{GS} =10V V _{DD} =30V
Q _{gs}	Gate-to-Source charge	—	18	—		
Q _{gd}	Gate-to-Drain("Miller") charge	—	28	—		
t _{d(on)}	Turn-on delay time	—	18.2	—	nS	V _{DD} =30V I _D =2A, R _L =15Ω R _G =2.5Ω V _{GS} =10V
t _r	Rise time	—	15.6	—		
t _{d(off)}	Turn-Off delay time	—	70.5	—		
t _f	Fall time	—	13.8	—	pF	V _{GS} =0V V _{DS} =25V f=1.0MHZ
C _{iss}	Input capacitance	—	3150	—		
C _{oss}	Output capacitance	—	300	—		
C _{rss}	Reverse transfer capacitance	—	240	—		

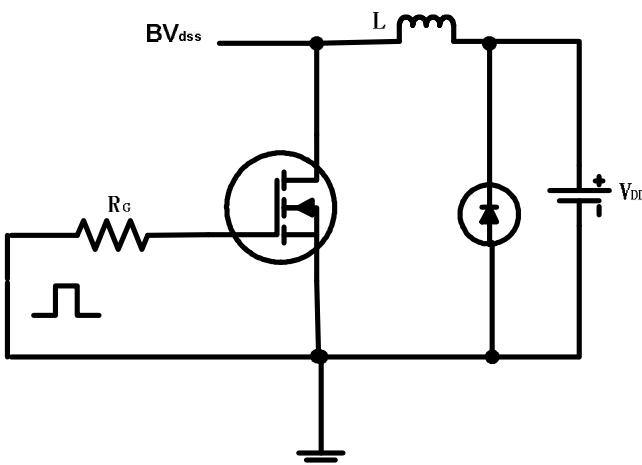
Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I _S	Continuous Source Current. (Body Diode)	—	—	84	A	MOSFET symbol showing the integral reverse p-n junction diode.
I _{SM}	Pulsed Source Current (Body Diode) ①	—	—	310		
V _{SD}	Diode Forward Voltage	—	—	1.3	V	T _J =25°C, I _S =60A, V _{GS} =0V ③
t _{rr}	Reverse Recovery Time	—	57	—	nS	T _J =25°C, I _F =75A
Q _{rr}	Reverse Recovery Charge	—	107	—	μC	di/dt=100A/μs ③
t _{on}	Forward Turn-on Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _s + LD)				

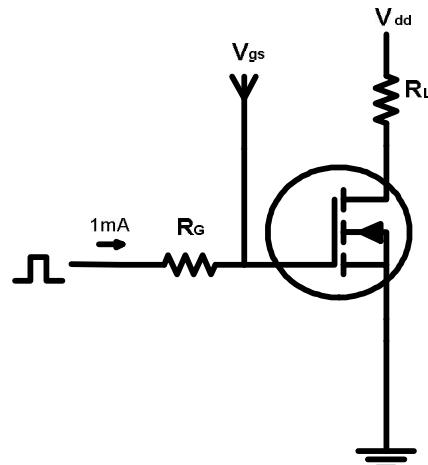
Notes:

- ① Repetitive rating; pulse width limited by max junction temperature.
- ② Test condition: L = 0.3mH, V_{DD} = 30V, I_D=37A.
- ③ Pulse width≤300μs, duty cycle≤1.5% ; R_G = 25Ω Starting T_J = 25°C.

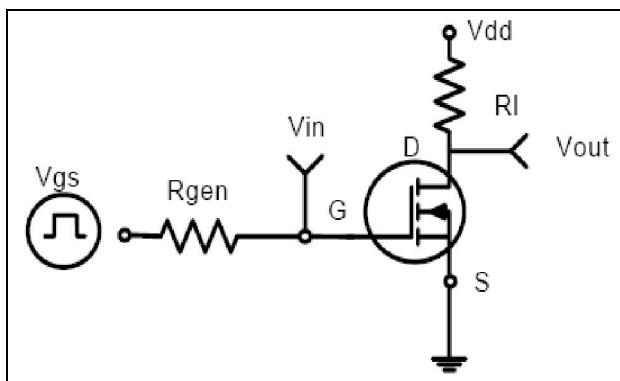
EAS Test Circuit



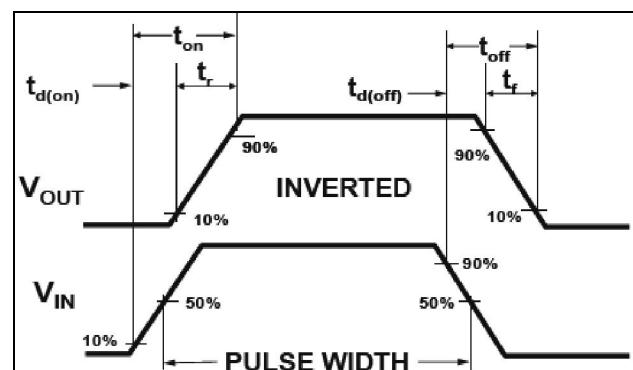
Gate Charge Test Circuit

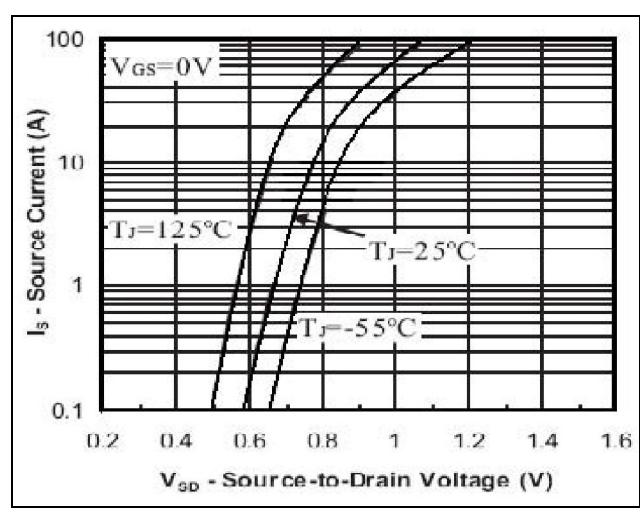
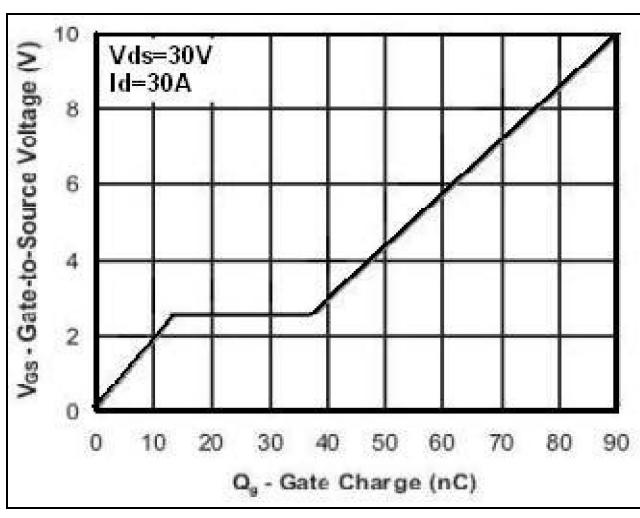
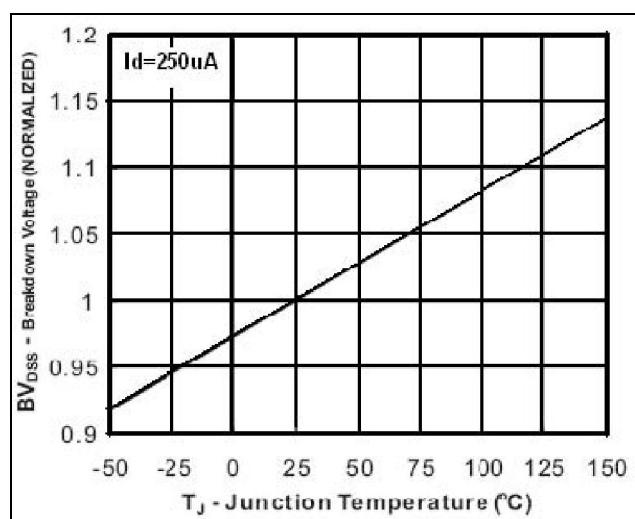
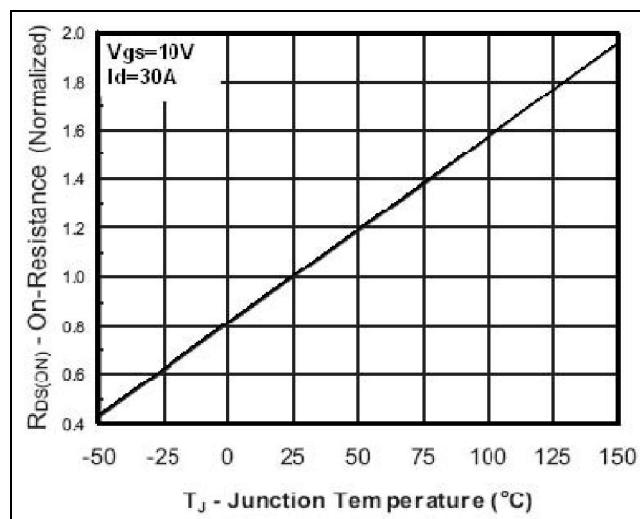
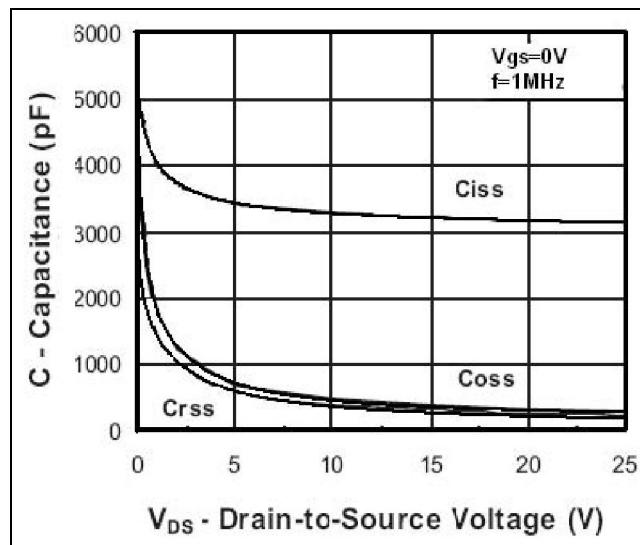
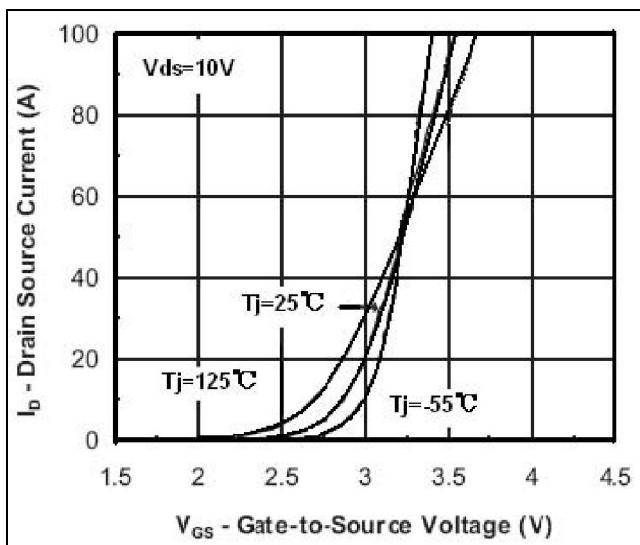


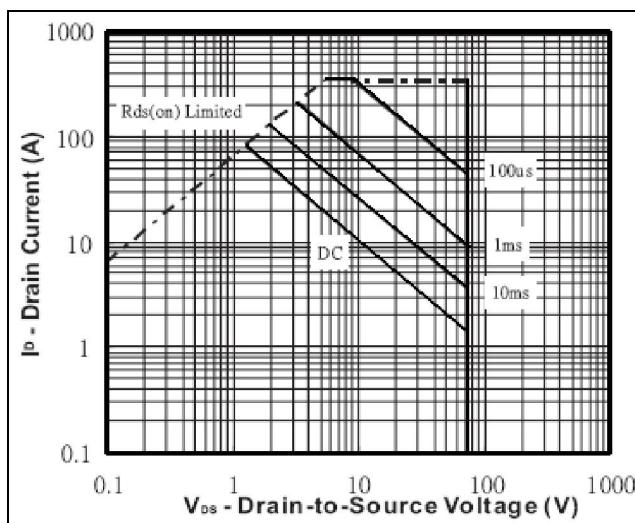
Switch Time Test Circuit



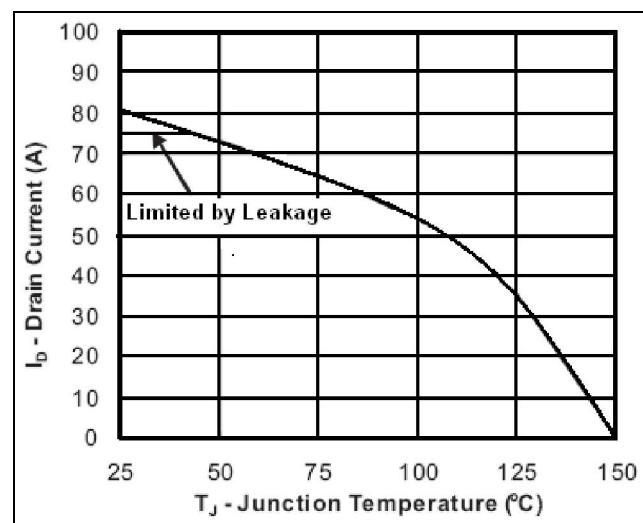
Switch Waveform



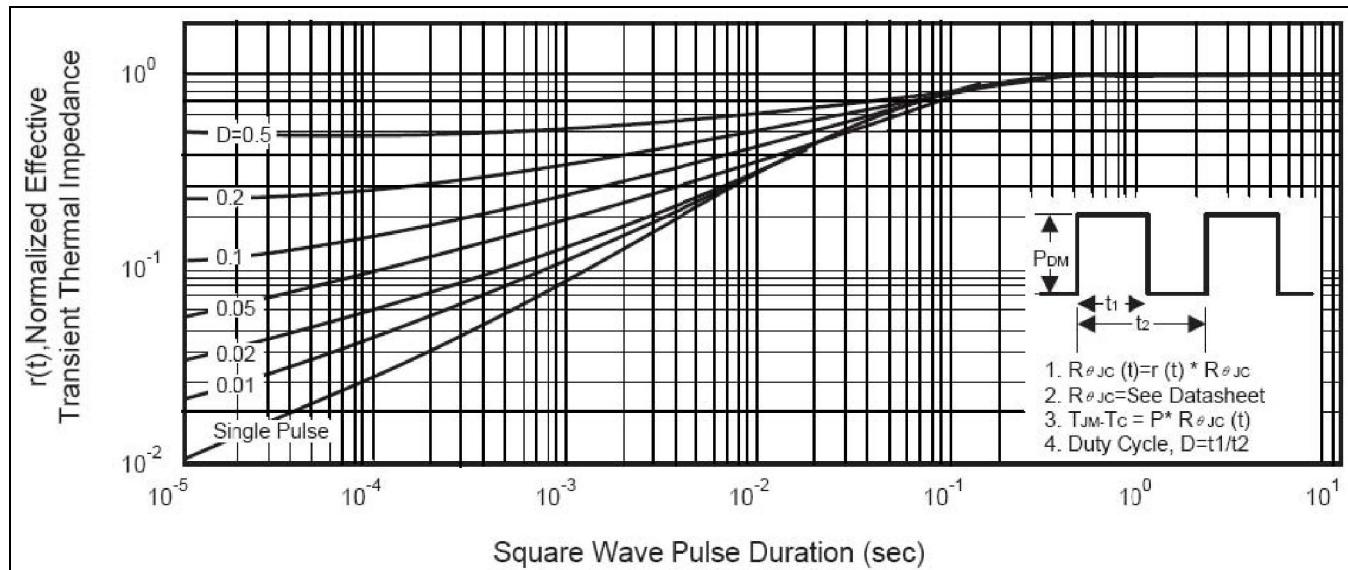




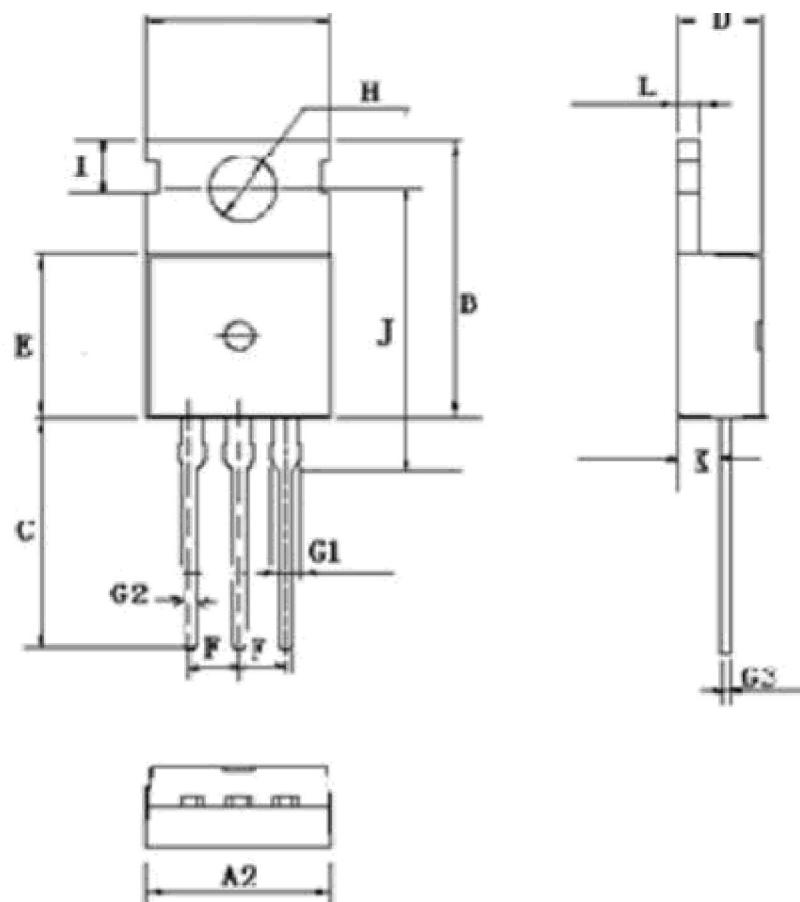
Safe Operation Area



Max Drain Current vs. Junction



Transient Thermal Impedance Curve

TO-220 MECHANICAL DATA

TO-220 3L

SYMBOL	DIMENSIONS
A(mm)	9.66~10.28
A2(mm)	9.80~10.20
B(mm)	15.6~15.8
C(mm)	12.70~14.27
D(mm)	4.30~4.70
E(mm)	8.59~9.40
F(mm)	2.54 (nom)
G1(mm)	1.42~1.62
G2(mm)	0.70~0.95
G3(mm)	0.45~0.60
H(mm) dia.	3.50~3.70
I(mm)	2.7~2.9
J(mm)	15.70~16.25
K(mm)	2.20~2.90
L(mm)	1.15~1.40
M(mm)	0.5